

Application/Control No.	Applicant(s)/Patent under Reexamination
10/616,696	SUGITA ET AL.
Examiner	Art Unit
Dah-Wei D. Yuan	1745

Dah-Wei D. Yuan

SEARCHED						
Class	Subclass	Date	Examiner			
429	12	7/11/2007	DWY			
429	34	7/11/2007	DWY			
429	38	7/11/2007	DWY			
			:			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
429	12	7/11/2007	DWY		
429	34	7/11/2007	DWY		
429	38	7/11/2007	DWY		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
		DATE	EXMR	
EAST		7/11/2007	DWY	
Inventorship Search		7/11/2007	DWY	